

**Search Notes**

Application/Control No.

10/764,481

Examiner

MARK A. MAIS

Applicant(s)/Patent under  
Reexamination

HIYAMA ET AL.

Art Unit

2619

**SEARCHED**

Class	Subclass	Date	Examiner
370	310 328 329	8/18/2008	MAM
	331 338 351		
	352 353		
	389 392		
	401 469		
	474 475 476		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2007	MAM
See Attached Electronic Search	6/16/2007	MAM
See Attached Electronic Search [updated]	3/30/2008	MAM
See Attached Electronic Search [updated]	8/18/2008	MAM